

Abstract

The image inspection device 100 for the electronic component 1 comprises a position detection means 10 for detecting a product position PP based on a product image P, an image correction means 20 for generating a corrected product image Pc by correcting the product image P based on the product position PP, a first inspection means 30 for performing a first inspection T1 having a first inspection logic L1 based on the corrected product image Pc and outputting a first inspection result T1R, a salvage inspection means 40 for executing a salvage inspection Tk having a salvage inspection logic Lk different from the first inspection logic L1 when the first inspection result T1R satisfies a specific condition in the first inspection logic L1 and outputting a salvage inspection result TkR, and an overall judgment means 50 for making an overall judgment of the electronic component 1 based on the first inspection result T1R and the salvage inspection result TkR.